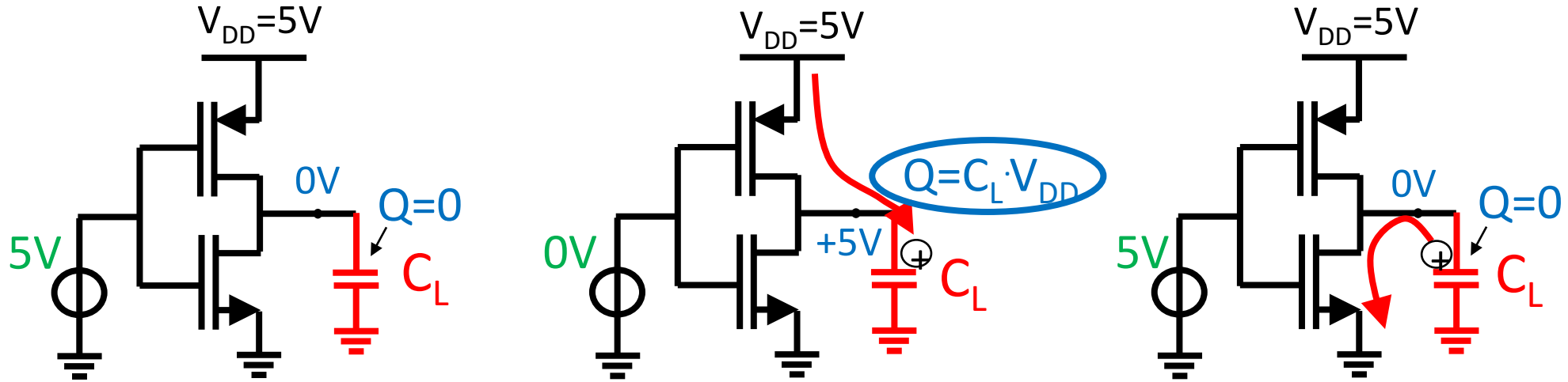
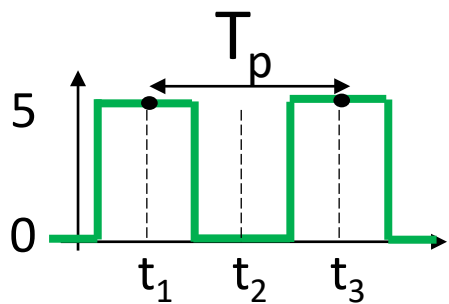


# Recap : Dinamic Power consumption of a CMOS



Charge  $Q$  started at  $V_{DD}=+5V$  and finished to ground in the time of a period  $T_p$



$$P \Big|_{T_p} = V_{DD}^2 \cdot C \cdot f$$

$V_{DD}$  (5V → 3.3V → 1.9V → ...) BUT : Reduces Noise margin  
 $C$  (90nm → 26nm → 11nm → ...) Connections btwn CMOS as short as possible  
 $f$  (Linearly increase with frequency of operation (today 3.7GHz).)

# Example 1

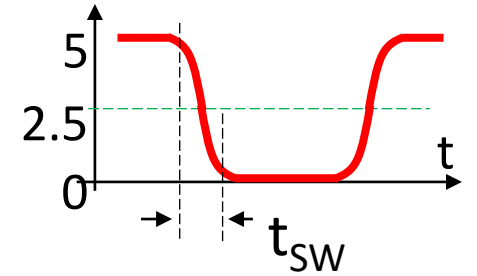
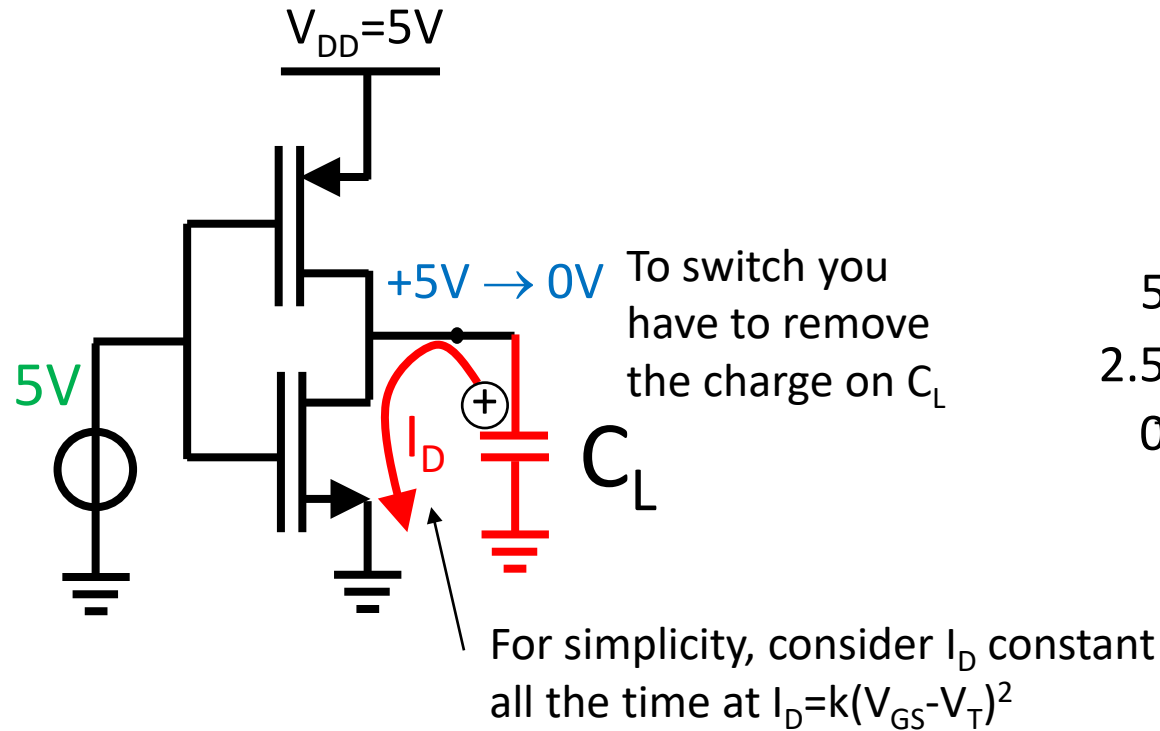
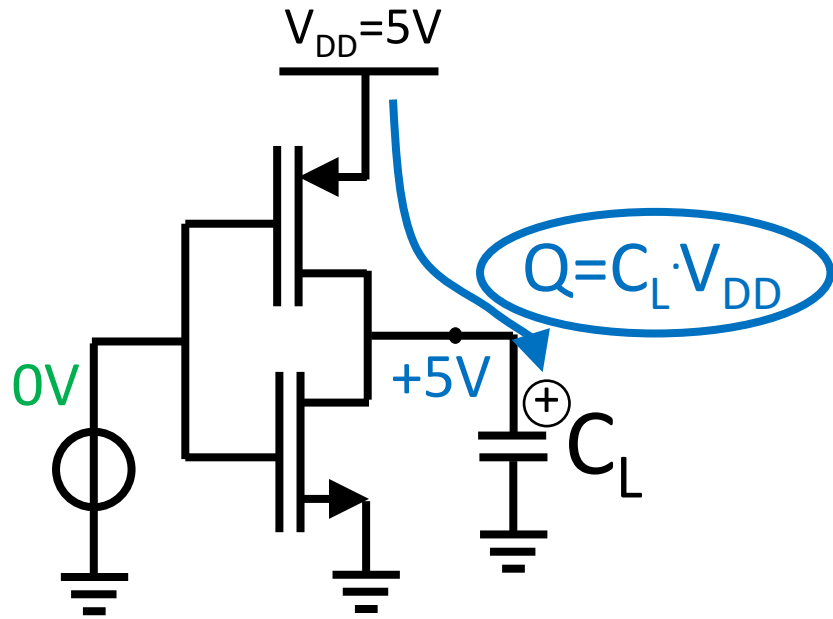
A microprocessor dissipates 25W when it works at a clock frequency  $f_{ck}=1.2\text{GHz}$  and 18W when working at  $f_{ck}=600\text{MHz}$ . Calculate the static power dissipated by the processor.

The power dissipated statically by the microprocessor is independent of the frequency of operation.

Instead, the dynamic power has a linear dependence on frequency as  $P|_{T_p} = V_{DD}^2 \cdot C \cdot f$

# Recap : Switching time of a CMOS inverter

$$I = \frac{Q}{t}$$



$$t_{sw} = \frac{Q}{I_D} \approx \frac{C_L \cdot V_{DD}}{k(V_{GS} - V_T)^2} = \frac{\frac{\epsilon_{ox}}{x_{ox}} W \cdot L \cdot V_{DD}}{\frac{1}{2} \mu \frac{\epsilon_{ox}}{x_{ox}} \frac{W}{L} (V_{DD} - V_T)^2} = \frac{L^2 \cdot V_{DD}}{\frac{1}{2} \mu (V_{DD} - V_T)^2}$$

Small transistors (again)

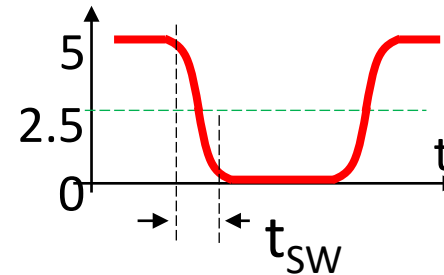
Voltage supply NOT too small

# Example 2

Let us consider again a very advanced computer having a CPU with 6nm technology (with  $x_{ox}=2\text{nm}$ ), transistors with a threshold voltage  $V_T=0.45\text{V}$  and voltage supply of  $0.9\text{V}$ .

Estimate the switching time,  $t_{sw}$ , of each CMOS gate.

$$t_{sw} = \frac{Q}{I_D} = \frac{L^2 \cdot V_{DD}}{\frac{1}{2}\mu(V_{DD} - V_T)^2}$$



**ELECTRONIC SYSTEMS and TECHNOLOGIES**

**Master in Management Engineering**

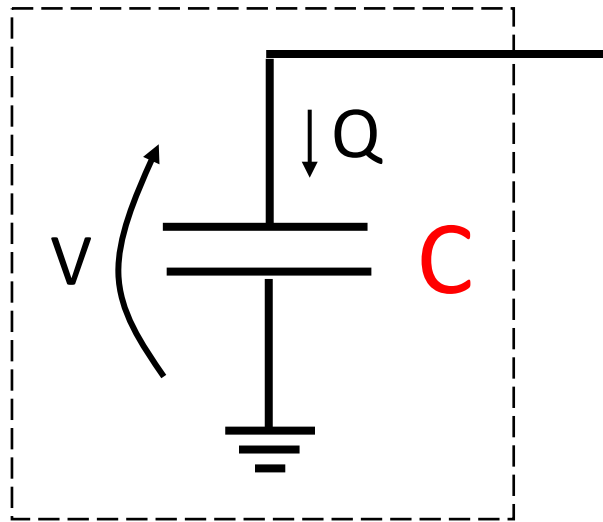
*Prof. Marco Sampietro*

GROUND CONCEPTS ON ELECTRONICS

**Memory devices - DRAM**

# The capacitor as a memory device

$$V = \frac{Q}{C}$$



*Memory cell*

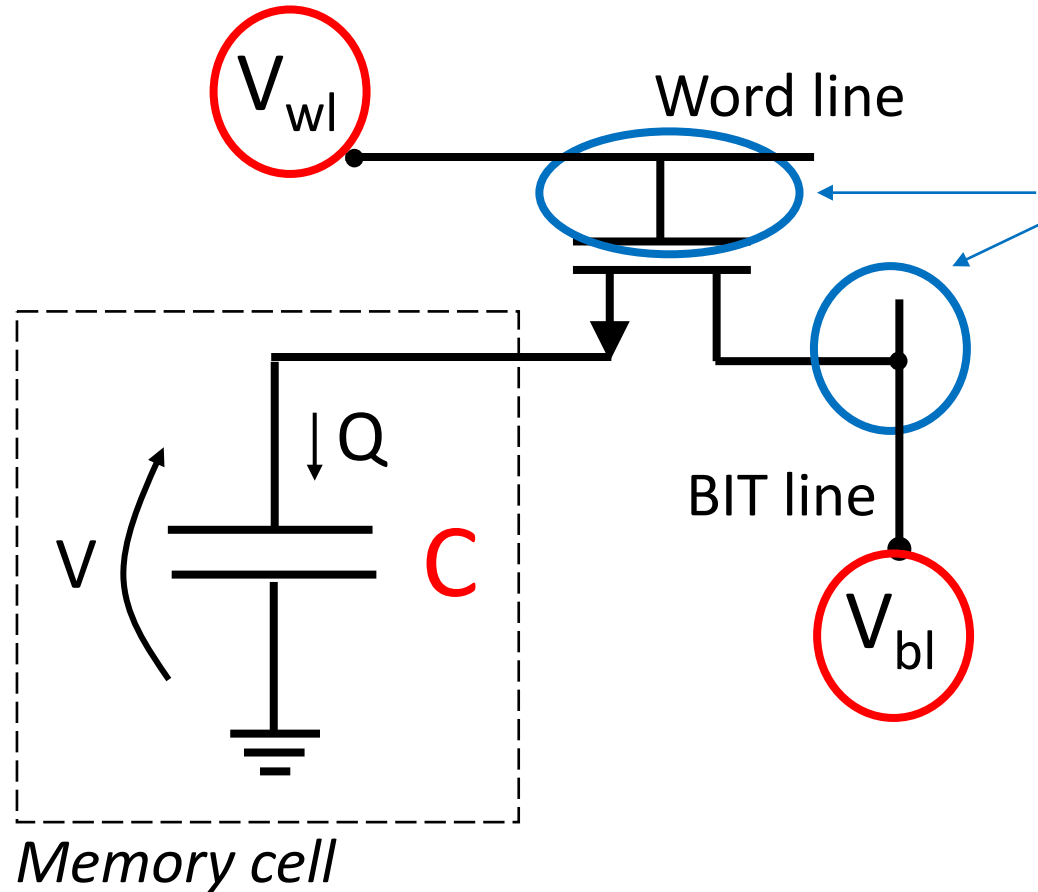
Charge IN  $\rightarrow$  V up  $\rightarrow$  Logic 1

Charge Q=0  $\rightarrow$  V=0V  $\rightarrow$  Logic 0

How to **write** and/or **read** the capacitance ?

# Transistor as a switch to access the Capacitor

$$V = \frac{Q}{C}$$



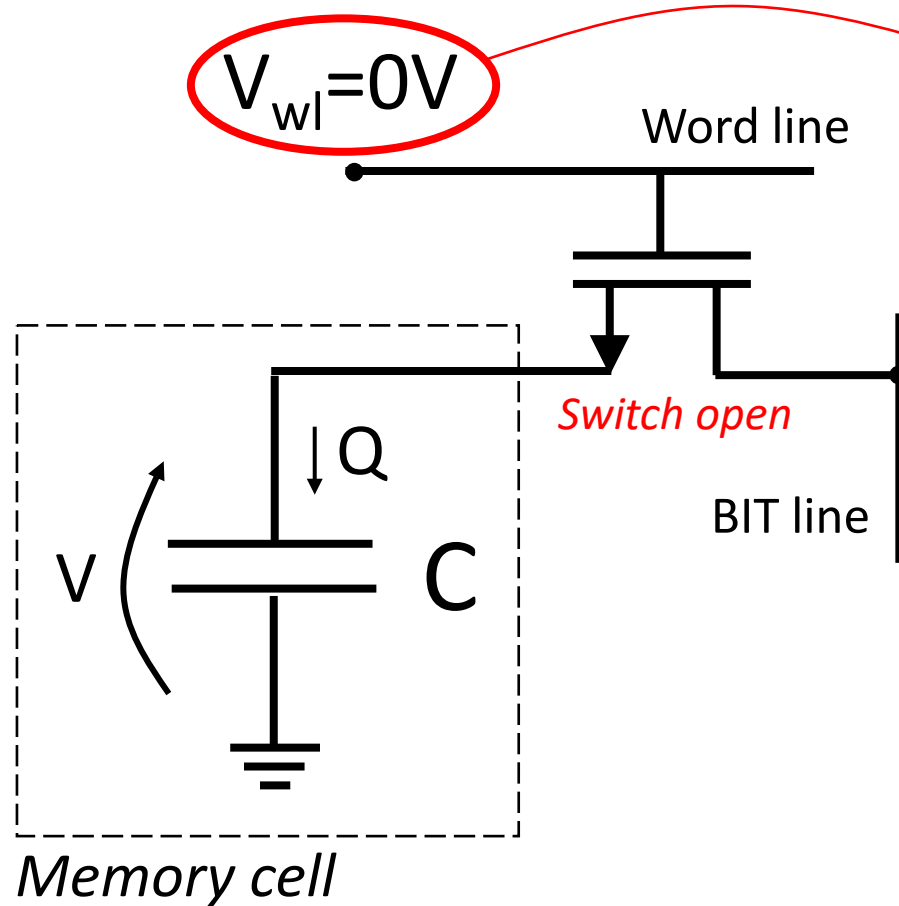
The Gate and the Drain are individually available, to have full control of the switch

Many memory cells require many switch transistors :

- All Drains in a column are connected together (BIT LINE)
- All Gates in a row are connected together (WORD LINE)

Voltages  $V_{wl}$  and  $V_{bl}$  determine the operation of the switch

# Memory cell disconnected : storage of information



nMOS is OFF  
(independently of C value, 0 or 1 logic)

Capacitor is disconnected

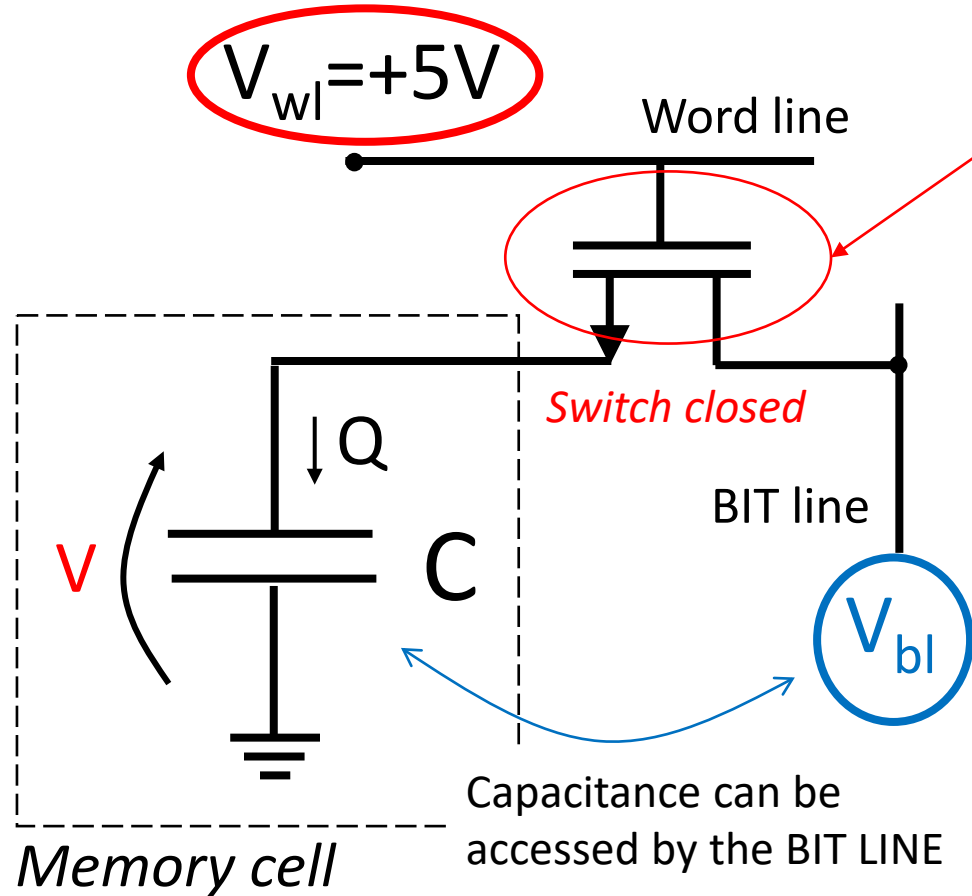
Capacitor maintains its value

Charge in C can not be modified by  
the BIT line



# Memory cell connected : switch closed

$V_T=0.8V$  and  $K=7mA/V^2$



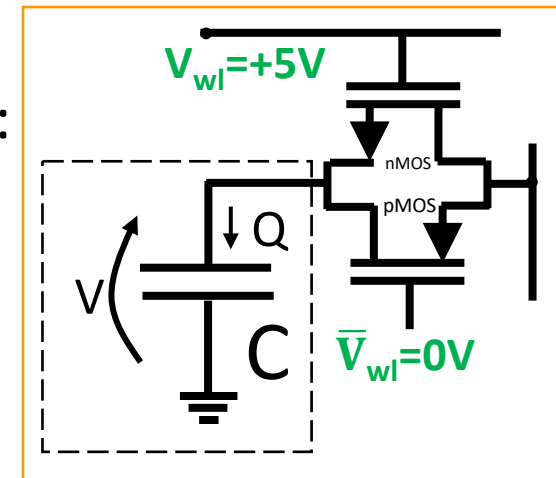
nMOS is ON

Reading on the BIT LINE :

$V=0V$	$V_{bl}=0$
$V=1V$	$V_{bl}=1V$
$V=2V$	$V_{bl}=2V$
$V=3V$	$V_{bl}=3V$
$V=4.2V$	$V_{bl}=4.2V$
$V=5V$	<del><math>V_{bl}=4.2V</math></del>
	$V_{bl}=5V$

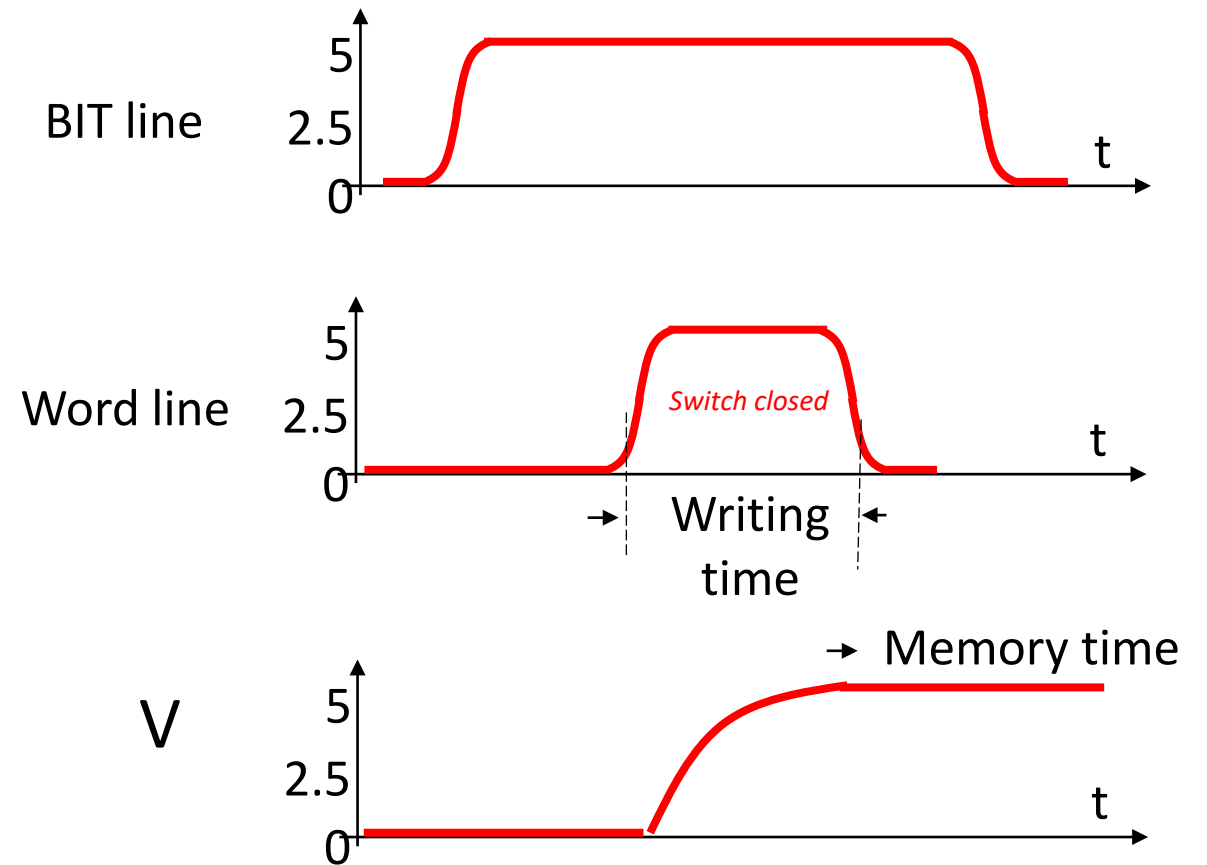
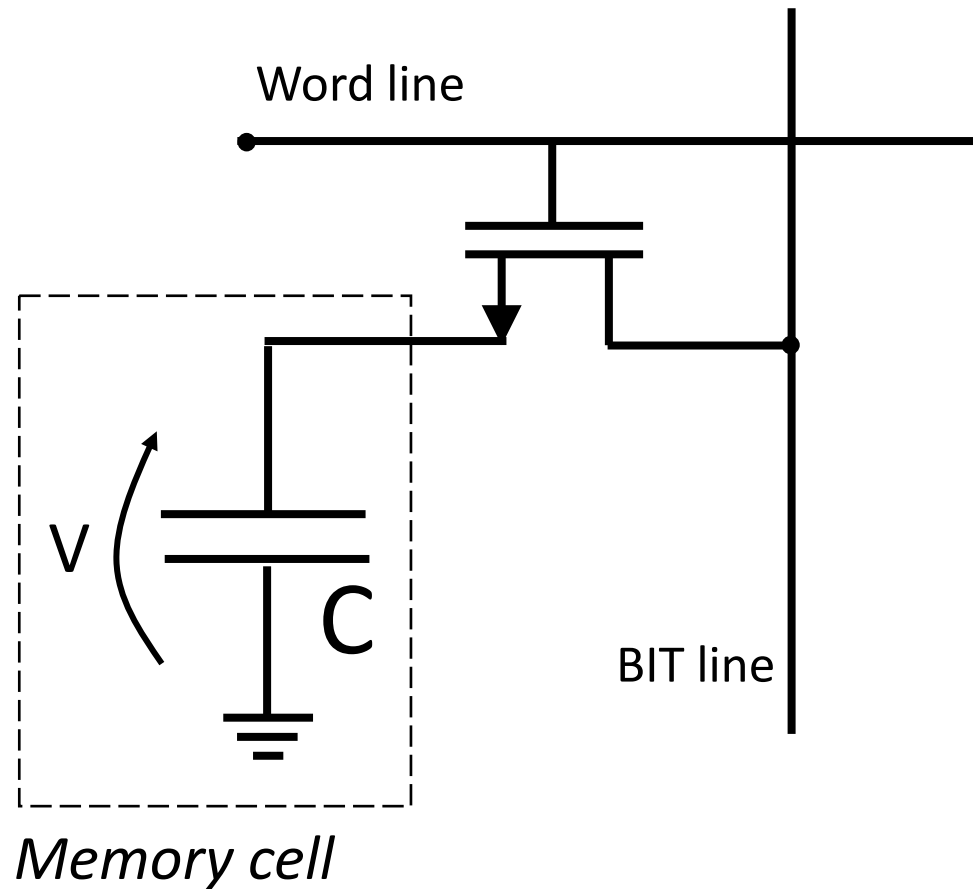
Capacitance can be accessed by the BIT LINE

Solved by :



Charge in  $C$  can be modified by the BIT line, by a proper voltage  $V_{bl}$  (0 or 5V).

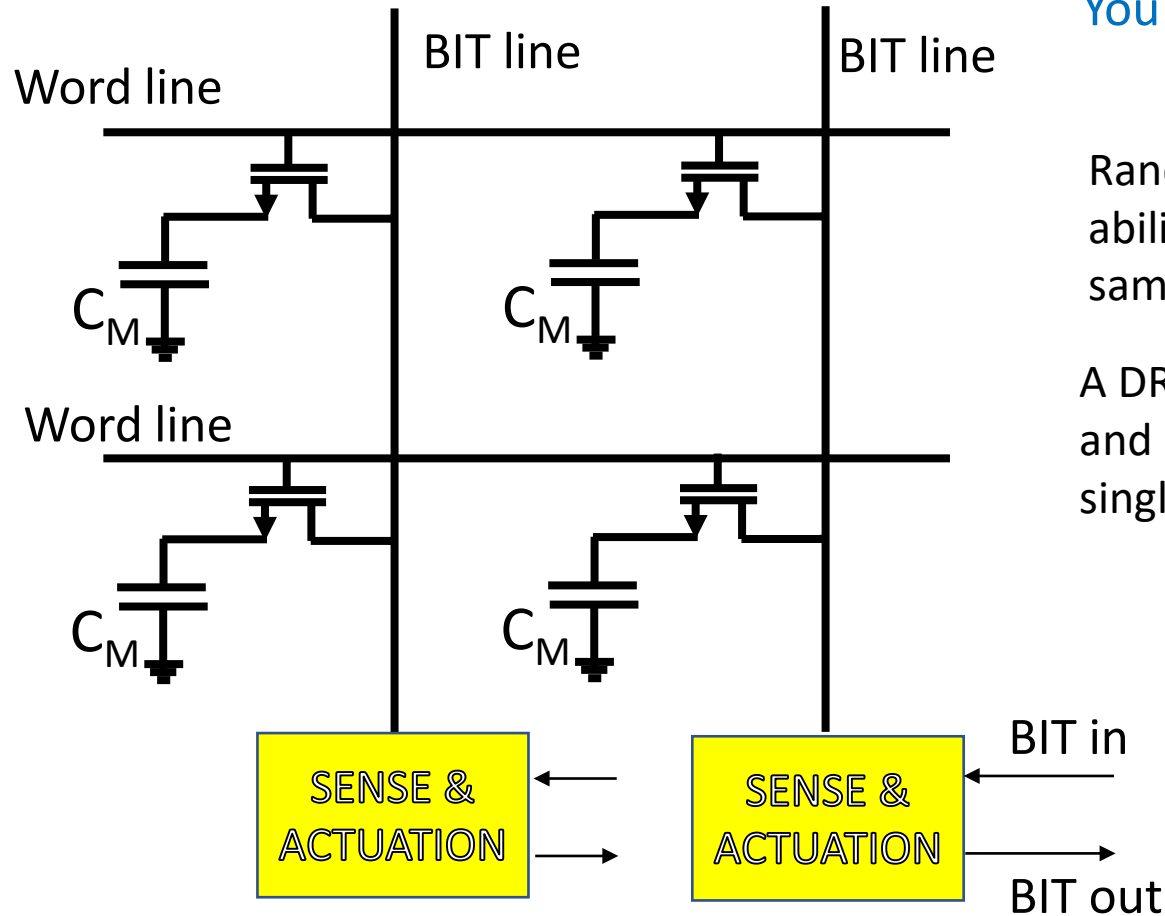
# Example of writing a «1»



# DRAM – Dynamic Random-Access Memory



You can address any cell at your will



Random Access Memory (RAM) is popular because of its ability to access any location in memory with roughly the same time delay.

A DRAM cell is consists of only two components, a transistor, and a capacitor, both extremely small as billions can fit on a single memory chip, allowing for high densities at a lower cost.

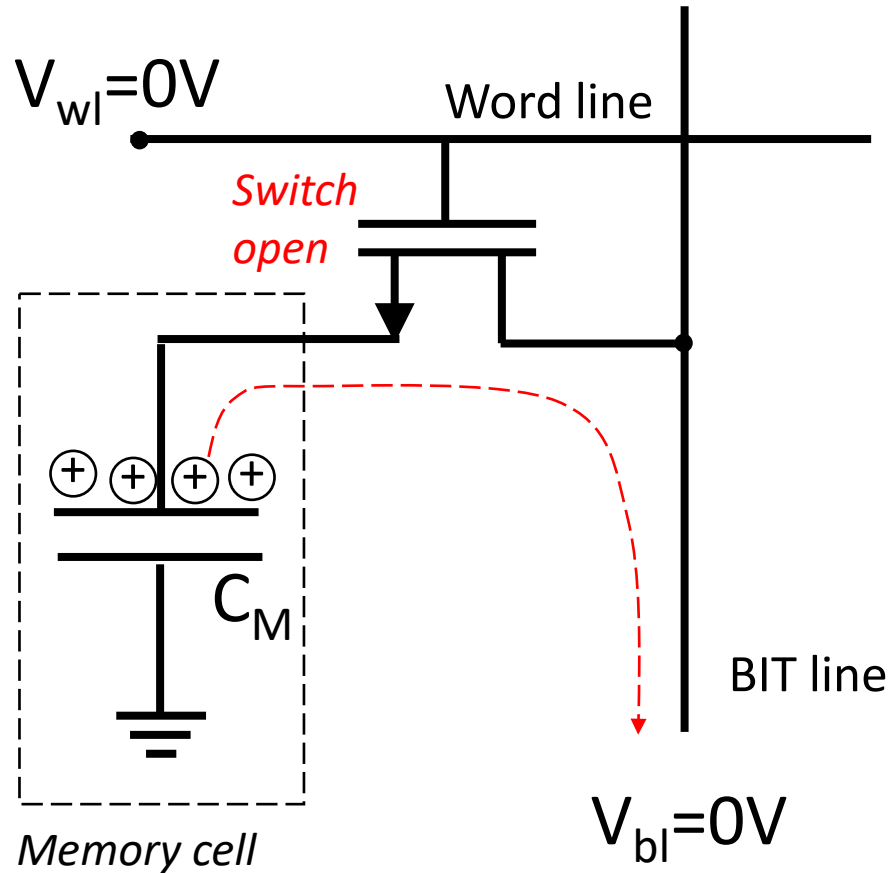
When reading

Sense amplifier

When writing

delivering a charge to  $C_M$

# DRAM – Dynamic Random-Access Memory



Time to retain the information ( $\tau$ ) :

$$\tau = C_M \cdot R_{off} = 10\text{fF} \cdot 10^4\text{G}\Omega = 0.1\text{ s} !$$

$C_M$  can not be made bigger because it will occupy too much area and cost too much.

This value is equivalent to about 100fA of leakage current



**NEED of REFRESH**  
(every 100ms)

Because of the dynamic nature of memory cells, DRAM consumes a relatively large amount of power.

When a MOSFET is OFF there are still very small currents

Charge in  $C_M$  «leaks» through the MOSFET to ground

# DRAM : summary

Is VOLATILE

Information disappears when Voltage supply is switched OFF

Is DYNAMIC

Need a refresh of the information (automatic and cycling reading of all the memory cells and refreshing)

Is RANDOM ACCESS

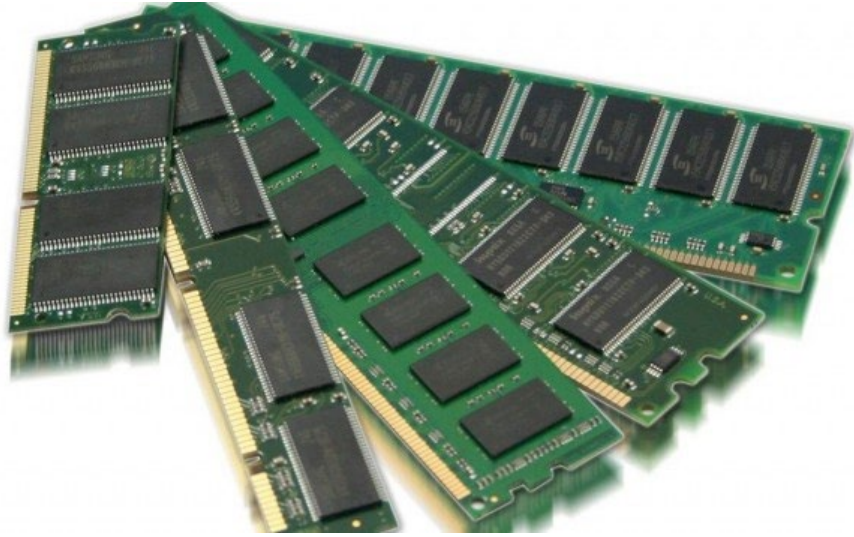
You can address every single memory cell (or a block of them) at your will in any moment

Is FAST

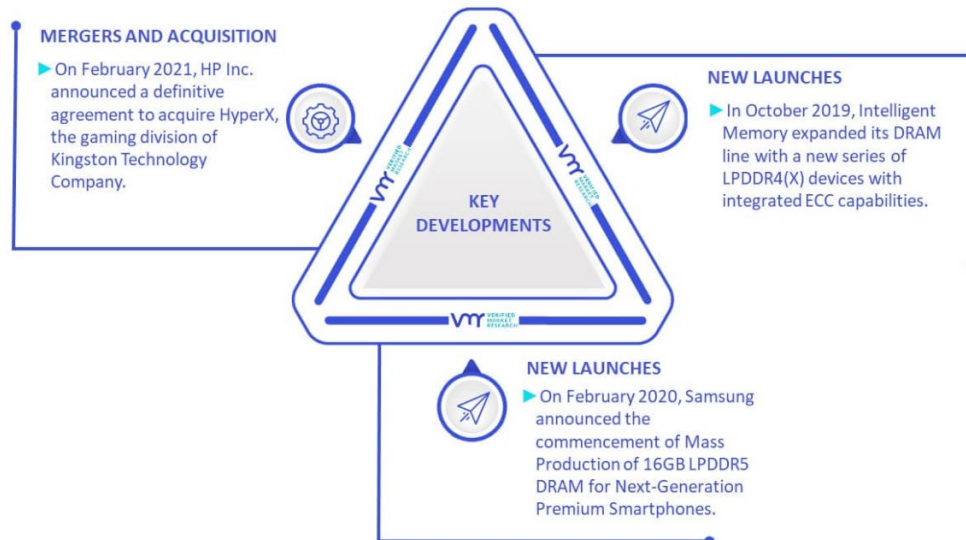
The data transfer rate for the 16GB LPDDR5 comes in at 5,500 megabits per second.

The LPDDR4 memories run at very high speeds with very low operating voltages and power consumption. They are made suitable for automotive applications, with design operability featuring higher temperature ranges up to 125°C and being AEC-Q100-qualified.

# DRAM : market and players



The Dynamic Random Access Memory (DRAM) market was valued at USD 66.8 billion in 2020 and is expected to cross the USD 100 billion mark by the end of 2026 by witnessing a CAGR of approximately 7% for the period 2020-2026.



The major players are Samsung Electronics, SK HYNIX, Micron Technology, Kingston Technology, Nanya Technology, Winbond, Transcend Information.

End of the lesson